

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of : Customer Number: 20277
Isao Hasegawa, et al. : Confirmation Number:
Serial No.: : Group Art Unit:
Filed: September 11, 2003 : Examiner: Unknown
For: METHOD OF FABRICATING SEMICONDUCTOR DEVICE

INFORMATION DISCLOSURE STATEMENT

Mail Stop IDS
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered during the prosecution of this application, and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed within three months of the U.S. filing date OR before the mailing date of a first Office Action on the merits. No certification or fee is required.

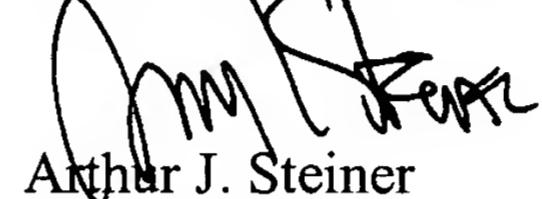
The relevance of AM-LCD '02, Digest of Technical Papers, July 10-12, 2002, pp. 227-230 is discussed in the present specification.

Serial No.:

Please charge any shortage in fees due in connection with the filing of this paper, including extension of time fees, to Deposit Account 500417 and please credit any excess fees to such deposit account.

Respectfully submitted,

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INFORMATION DISCLOSURE CITATION IN AN APPLICATION (PTO-1449)			ATTY. DOCKET NO. 57810-074	SERIAL NO.			
			APPLICANT Isao Hasegawa, et al.				
			FILING DATE September 11, 2003	GROUP			
U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear		
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FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Codes-Number & Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation	
						Yes	No
		JP P2002-93702A	03/29/2002	SANYO ELECTRIC CO LTD		(Japan w/English Abstract)	
		JP P2001-189458A	07/10/2001	SANYO ELECTRIC CO LTD		(Japan w/English Abstract)	
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.					
		"Large Grain Poly-Si TFTs by Scanning CW Laser Crystallization," Hara et al. AM-LCD '02, Digest of Technical Papers, July 10-12, 2002 pp. 227-230					
		Extended Abstracts (The 48th Spring Meeting, 2001); The Japan Society of Applied Physics and Related Societies. JSAP Catalog Number: AP 011109-02 (03/28/2001) pg. 900					
		21st Century Version "A Handbook of Applied Forming for Thin Film," April 22, 2003					
EXAMINER				DATE CONSIDERED			

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1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.